Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/684,317	HOFMEISTER ET AL.
Examiner	**Art Unit**
Ernest F. Karlsen	2829

SEARCHED			
Class	Subclass	Date	Examiner
324	158.1	4/1/2005	E.F.K.
327	551	4/1/2005	E.F.K.
326	80 81	4/1/2005	E.F.K.
257	528	4/1/2005	E.F.K.
323	220 232 233	4/1/2005	E.F.K.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
shift adj2 voltage with level and power and semiconductor filter same locat$ same (chip or die) same power	4/1/2005	E.F.K.